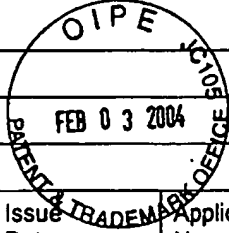


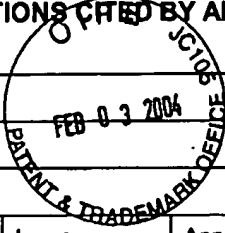
U.S. Department of Commerce, Patent and Trademark Office (PTO Form 1449 modified)				Docket No. AMAT/5163P1/DISP LAY/AHRDWR/RKK		Serial No. 10/321,289	
LIST OF PATENTS AND PUBLICATIONS CITED BY APPLICANT				Applicant Kim, et al.		Confirmation No.: 2911	
(Use several sheets if necessary)				Filing Date December 17, 2002		Group 3742	
Examiner							
							
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*Examiner Initial		Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date if Appropriate
ST	A1	4,486,487	12/04/84	Skarp	428	216	04/25/1983
	A2	4,767,494	08/30/88	Kobayashi et al.	156	606	09/19/1986
	A3	4,806,321	02/21/89	Nishizawa et al.	422	245	07/21/1985
	A4	4,813,846	03/21/89	Helms	414	744.1	04/29/87
	A5	4,829,022	05/09/89	Kobayashi et al.	437	107	12/09/1986
	A6	4,838,983	06/13/89	Schumaker et al.	156	613	03/18/1988
	A7	4,838,993	06/13/89	Aoki et al.	156	643	12/03/1987
	A8	4,840,921	06/20/89	Matsumoto	437	89	06/30/1988
	A9	4,845,049	07/04/89	Sunakawa	437	81	03/28/1988
	A10	4,859,625	08/22/89	Nishizawa et al.	437	81	11/20/1987
	A11	4,859,627	08/22/89	Sunakawa	437	81	07/01/1988
	A12	4,861,417	08/29/89	Mochizuki et al.	156	610	03/24/1988
	A13	4,876,218	10/24/89	Pessa et al.	437	107	09/26/1988
	A14	4,917,556	04/17/90	Stark et al.	414	217	05/26/89
	A15	4,927,670	05/22/1990	Erbil	427	255.3	06/22/1988
	A16	4,931,132	06/05/90	Aspnes et al.	156	601	10/07/1988
	A17	4,951,601	08/28/90	Maydan, et al.	118	719	06/23/89
	A18	4,960,720	10/02/90	Shimbo	437	105	08/24/1987
	A19	4,975,252	12/04/90	Nishizawa et al.	422	245	05/26/1989
	A20	5,000,113	03/19/91	Wang et al.	118	723	12/19/86
	A21	5,013,683	05/07/91	Petroff et al.	437	110	01/23/1989
	A22	5,028,565	07/02/1991	Chang, et al.	437	192	08/25/1989
	A23	5,082,798	01/21/92	Arimoto	437	108	09/27/1990
	A24	5,085,885	02/04/92	Foley et al.	477	38	09/10/1990
	A25	5,091,320	02/25/92	Aspnes et al.	437	8	06/15/1990
	A26	5,130,269	07/14/92	Kitahara et al.	437	111	04/25/1989
	A27	5,166,092	11/24/92	Mochizuki et al.	437	105	10/30/1990
	A28	5,173,474	12/22/1992	Connell, et al.	505	1	03/11/1991
Examiner <i>Shawna Sugue</i>				Date Considered <i>5/31/04</i>			
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SL	A29	5,186,718	02/16/93	Tepman et al.	29	25.01	04/15/91
	A30	5,205,077	04/27/93	Wittstock	51	165 R	08/28/91
	A31	5,234,561	08/10/93	Randhawa et al.	204	192.38	08/25/88
	A32	5,246,536	09/21/93	Nishizawa et al.	156	610	03/10/1989
	A33	5,250,148	10/05/93	Nishizawa et al.	156	611	11/12/1991
	A34	5,254,207	10/19/93	Nishizawa et al.	156	601	11/30/1992
	A35	5,256,244	10/26/93	Ackerman	156	613	02/10/1992
	A36	5,259,881	11/09/93	Edwards, et al.	118	719	05/17/91
	A37	5,270,247	12/14/93	Sakuma et al.	437	133	07/08/1992
	A38	5,278,435	01/11/94	Van Hove et al.	257	184	06/08/1992
	A39	5,286,296	02/15/94	Sato et al.	118	719	01/09/92
	A40	5,290,748	03/01/94	Knuuttila et al.	502	228	07/16/1992
	A41	5,296,403	03/22/94	Nishizawa et al.	437	133	10/23/1992
	A42	5,300,186	04/05/94	Kitahara et al.	156	613	04/07/1992
	A43	5,311,055	05/10/94	Goodman et al.	257	593	11/22/1991
	A44	5,316,615	05/31/94	Copel	117	95	03/09/1993
	A45	5,316,793	05/31/94	Wallace et al.	427	248.1	07/27/1992
	A46	5,330,610	07/19/94	Eres et al.	117	86	05/28/1993
	A47	5,336,324	08/09/94	Stall et al.	118	719	12/04/1991
	A48	5,338,389	08/16/94	Nishizawa et al.	117	89	04/21/1993
	A49	5,348,911	09/20/94	Jurgensen et al.	117	91	04/26/1993
	A50	5,395,791	03/07/95	Cheng et al.	437	105	10/20/1993
	A51	5,438,952	08/08/1995	Otsuka	117	84	01/31/1994
	A52	5,439,876	08/08/95	Graf et al.	505	447	08/16/1993
	A53	5,443,033	08/22/95	Nishizawa et al.	117	86	03/11/1994
SL	A54	5,455,072	10/03/95	Bension et al.	427	255.7	11/18/1992
Examiner <i>Shauntina Inoue</i>				Date Considered <i>5/31/09</i>			
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SE	A55	5,458,084	10/17/95	Thorne et al.	117	89	12/09/1993
	A56	5,469,806	11/28/95	Mochizuki et al.	117	97	08/20/1993
	A57	5,484,664	01/16/96	Kitahara et al.	428	641	01/21/1994
	A58	5,521,126	05/28/96	Okamura et al.	437	235	06/22/1994
	A59	5,527,733	06/18/96	Nishizawa et al.	437	160	02/18/1994
	A60	5,532,511	07/02/96	Nishizawa et al.	257	627	03/23/1995
	A61	5,540,783	07/30/96	Eres et al.	118	725	05/26/1994
	A62	5,561,735	10/01/1996	Camm	392	416	08/30/1994
	A63	5,580,380	12/03/1996	Liu, et al.	117	86	01/30/1995
	A64	5,601,651	02/11/97	Watabe	118	715	12/14/1994
	A65	5,609,689	03/11/97	Kato et al.	118	719	06/03/96
	A66	5,616,181	04/01/97	Yamamoto et al.	118	723 ER	11/21/1995
	A67	5,637,530	06/10/97	Gaines et al.	114	105	06/10/1996
	A68	5,641,984	06/24/97	Aftergut et al.	257	433	08/19/1994
	A69	5,644,128	07/01/97	Wollnik et al.	250	251	08/25/1994
	A70	5,667,592	09/16/97	Boitnott et al.	118	719	04/16/96
	A71	5,693,139	12/02/97	Nishizawa et al.	117	89	06/15/1993
	A72	5,695,564	12/09/97	Imahashi	118	719	08/03/95
	A73	5,705,224	01/06/98	Murota et al.	427	248.1	01/31/1995
	A74	5,707,880	01/13/98	Aftergut et al.	437	3	01/17/1997
	A75	5,730,801	03/24/98	Tepman et al.	118	719	08/23/94
	A76	5,730,802	03/24/98	Ishizumi et al.	118	719	12/27/1996
	A77	5,747,113	05/05/98	Tsai	427	255.5	07/29/1996
	A78	5,749,974	05/12/98	Habuka et al.	118	725	07/13/1995
	A79	5,788,447	08/04/98	Yonemitsu et al.	414	217	08/05/96
SE	A80	5,788,799	08/04/98	Steger, et al.	156	345	06/11/96
Examiner <i>Shauntara Inguia</i>				Date Considered <i>6/1/04</i>			
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*Examiner Initial		Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate
SH	A81	5,801,634	09/01/98	Young et al.	340	635	09/08/97
	A82	5,830,270	11/03/98	McKee et al.	117	106	08/05/1996
	A83	5,850,071	12/15/1998	Makiguchi, et al.	219	390	08/09/1996
	A84	5,851,849	12/22/98	Comizzoli et al.	438	38	05/22/1997
	A85	5,855,675	01/05/99	Doering et al.	118	719	03/03/1997
	A86	5,856,219	01/05/99	Naito et al.	438	241	08/18/97
	A87	5,858,102	01/12/99	Tsai	118	719	02/14/1998
	A88	5,866,213	02/02/99	Foster et al.	427	573	07/19/97
	A89	5,866,795	02/02/99	Wang et al.	73	1.36	03/17/97
	A90	5,882,165	03/16/99	Maydan et al.	414	217	09/10/97
	A91	5,882,413	03/16/99	Beaulieu et al.	118	719	07/11/97
	A92	5,904,565	05/18/1999	Nguyen, et al.	438	687	07/17/1997
	A93	5,923,056	07/13/99	Lee et al.	257	192	03/12/1998
	A94	5,923,985	07/13/99	Aoki et al.	438	301	01/14/1997
	A95	5,925,574	07/20/99	Aoki et al.	437	31	04/10/1992
	A96	5,928,389	07/27/99	Jevtic	29	25.01	10/21/96
	A97	5,942,040	08/24/99	Kim et al.	118	726	08/27/1997
	A98	5,947,710	09/07/1999	Cooper, et al.	418	63	06/16/1997
	A99	5,972,430	10/26/99	DiMeo, Jr. et al.	427	255.32	11/26/1997
	A100	6,001,669	12/14/99	Gaines et al.	438	102	07/21/1992
	A101	6,025,627	02/15/00	Forbes et al.	257	321	05/29/1998
	A102	6,036,773	03/14/00	Wang et al.	117	97	03/27/1997
	A103	6,043,177	03/28/00	Falconer et al.	502	4	01/21/1997
	A104	6,046,439	04/04/2000	Johnsgard, et al.	219	444.1	06/16/1997
	A105	6,051,286	04/18/00	Zhao et al.	427	576	08/22/97
	A106	6,062,798	05/16/00	Muka	414	416	06/13/96
Examiner <i>Shawntia Igua</i>					Date Considered <i>5/31/04</i>		
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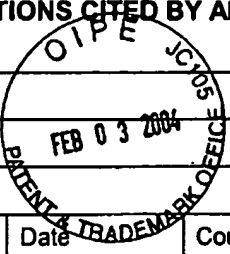


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	A108	6,084,302	07/04/00	Sandhu	257	751	12/26/95
	A109	6,086,677	07/11/00	Umotoy et al.	118	715	06/16/98
	A110	6,110,556	08/29/00	Bang, et al.	428	64.1	10/17/97
	A111	6,113,977	09/05/00	Soininen et al.	427	64	09/11/1997
	A112	6,117,244	09/12/00	Bang, et al.	118	715	03/24/98
	A113	6,124,158	09/26/00	Dautartas et al.	438	216	06/08/1999
	A114	6,130,147	10/10/00	Major et al.	438	604	03/18/1997
	A115	6,140,237	10/31/00	Chan et al.	438	687	04/19/99
	A116	6,140,238	10/31/00	Kitch	438	687	04/21/99
	A117	6,143,659	11/07/00	Leem	438	688	08/27/98
	A118	6,144,060	11/07/00	Park et al.	257	310	07/31/98
	A119	6,147,334	11/14/2000	Hannigan	219	544	01/29/1999
	A120	6,151,447	11/21/2000	Moore, et al.	392	418	11/25/1997
	A121	6,158,446	12/12/00	Mohindra et al.	134	25.4	09/04/98
	A122	6,174,809	01/16/2001	Kang, et al.	438	682	12/15/1998
	A123	6,203,613	03/20/2001	Gates, et al.	117	104	10/19/1999
	A124	6,206,967	03/27/01	Mak, et al.	118	666	06/14/00
	A125	6,207,302	03/27/2001	Sugiura, et al.	428	690	03/02/1998
	A126	6,248,605	06/19/2001	Harkonen, et al.	438	29	06/02/1999
	A127	6,271,148	08/07/01	Kao et al.	438	727	10/13/99
	A128	6,287,965	09/11/2001	Kang, et al.	438	648	02/23/2000
	A129	6,291,876	09/18/2001	Stumborg, et al.	257	632	08/20/1998
	A130	6,316,098	11/13/2001	Yitzchaik, et al.	428	339	03/23/1999
✓	A131	2001/0031562	10/18/2001	Raaijmakers, et al.	438	770	02/22/2001
✓	A132	2001/0034123	10/25/2001	Jeon, et al.	438	643	04/06/2001
Sh	A133	2001/0041250	11/15/01	Werkhoven et al.	428	212	03/06/01

Examiner *Shawntina Angwa* Date Considered *5/3/09*

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Examiner	Shawntia - Inguia	Date Considered	6/1/09
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Examiner <i>Shawntina Ingua</i>					Date Considered <i>6/1/04</i>			
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


U.S. Department of Commerce, Patent and Trademark Office (PTO Form 1449 modified)					Docket No. AMAT/5163P1/DISP LAY/AHRDWR/RKK		Serial No. 10/321,289	
LIST OF PATENTS AND PUBLICATIONS CITED BY APPLICANT					Applicant Kim, et al.		Confirmation No.: 2911	
(Use several sheets if necessary)					Filing Date December 17, 2002		Group 3742	
Examiner								
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Examiner <i>Shawntina - Jague</i>					Date Considered <i>6/1/04</i>			
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Examiner <i>Shauntina Igua</i>					Date Considered <i>6/1/04</i>			
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Examiner <i>Shauntina Augus</i>					Date Considered <i>5/31/04</i>			
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Examiner <i>Shaw-Tina Ingua</i>					Date Considered <i>6/1/04</i>			
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Examiner <i>Shawntina Augue</i>					Date Considered <i>6/1/09</i>			
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(Use several sheets if necessary)		Filing Date December 17, 2002	Group 3742
Examiner			
OTHER ART			
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Stf	C1	Hultman, et al., "Review of the thermal and mechanical stability of TiN-based thin films", <i>Zeitschrift Fur Metallkunde</i> , 90(10) (Oct. 1999), pp. 803-813.	
	C2	Klaus, et al., "Atomic Layer Deposition of SiO <sub>2</sub> Using Catalyzed and Uncatalyzed Self-Limiting Surface Reactions", <i>Surface Review &amp; Letters</i> , 6(3&4) (1999), pp. 435-448.	
	C3	Yamaguchi, et al., "Atomic-layer chemical-vapor-deposition of silicon dioxide films with extremely low hydrogen content", <i>Appl. Surf. Sci.</i> , Vol. 130-132 (1998), pp. 202-207.	
	C4	George, et al., "Surface Chemistry for Atomic Layer Growth", <i>J. Phys. Chem.</i> , Vol. 100 (1996), pp. 13121-131.	
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LIST OF PATENTS AND PUBLICATIONS CITED BY APPLICANT (Use several sheets if necessary)		Applicant Kim, et al.	Confirmation No.: 2911
Examiner		Filing Date December 17, 2002	Group 3742
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SL	C34	Abstracts of search results re atomic layer deposition, search dated January 24, 2002	
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<u>Docket Number</u>	<u>Serial or Patent Number</u>	<u>Filing or Issue Date</u>	<u>Inventor/ Applicant</u>
219288US2 PCT*	10/049,293	04/30/02	ITO, et al.
246590US90 DIV	10/732,296	12/11/03	ITO, et al.
246909US90 CONT	10/746,081	12/29/03	HIRAMATSU, et al.
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Set	219288US2PCT*	10/049,293	04/30/02	ITO, et al.
Set	242768US90 CONT	10/663,681	09/17/03	ITO, et al.

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